

## N-Channel MOSFET



Lead Free Package and Finish

## Applications:

- Adaptor
- Charger
- SMPS

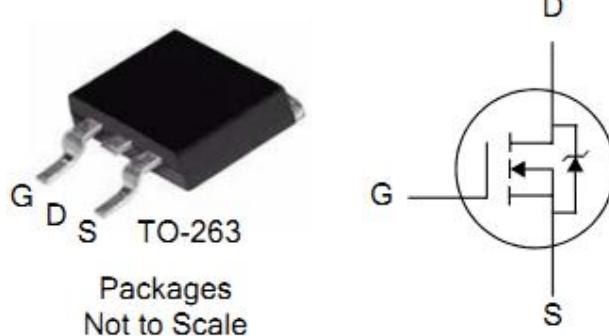
$V_{DSS}$	$R_{DS(ON)}$ (Typ.)	$I_D$
85V	6mΩ	120A

## Features:

- RoHS Compliant
- Low ON Resistance
- Low Gate Charge
- Peak Current vs Pulse Width Curve
- Inductive Switching Curves

## Ordering Information

PART NUMBER	PACKAGE	BRAND
FTB07N08N	TO-263	IPS

Absolute Maximum Ratings  $T_C=25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	FTP07N08N	Units
$V_{DSS}$	Drain-to-Source Voltage	85	V
$I_D$	Continuous Drain Current	120	A
	Continuous Drain Current $T_C = 100^\circ\text{C}$	85	A
$I_{DM}$	Pulsed Drain Current (NOTE *1)	480	A
$P_D$	Power Dissipation	208	W
	Derating Factor above $25^\circ\text{C}$	1.8	W/ $^\circ\text{C}$
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulse Avalanche Energy(NOTE *2)	650.25	mJ
$T_L$	Maximum Temperature for Soldering	300	
$T_J$ and $T_{STG}$	Operating Junction and Storage Temperature Range	150, -55 to 150	$^\circ\text{C}$

## Thermal Resistance

Symbol	Parameter	Max.	Units	Test Conditions
$R_{\theta JC}$	Junction-to-Case	0.55	$^\circ\text{C}/\text{W}$	Water cooled heatsink, $P_D$ adjusted for a peak junction temperature of $+150^\circ\text{C}$ .
$R_{\theta JA}$	Junction-to-Ambient	65.2		1 cubic foot chamber, free air.

**OFF Characteristics**  $T_C=25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$\text{BV}_{\text{DSS}}$	Drain-to-Source Breakdown Voltage	85	--	--	V	$V_{\text{GS}}=0\text{V}, I_D=250\mu\text{A}$
$I_{\text{DSS}}$	Drain-to-Source Leakage Current	--	--	1	$\mu\text{A}$	$V_{\text{DS}}=85\text{V}, V_{\text{GS}}=0\text{V}$ $T_J=25^\circ\text{C}$
		--	--	100		$V_{\text{DS}}=68\text{V}, V_{\text{GS}}=0\text{V}$ $T_J=100^\circ\text{C}$
$I_{\text{GSS}}$	Gate-to-Source Forward Leakage	--	--	+100	$\text{nA}$	$V_{\text{GS}}=+20\text{V}$
	Gate-to-Source Reverse Leakage	--	--	-100		$V_{\text{GS}}= -20\text{V}$

**ON Characteristics**  $T_J=25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$R_{\text{DS}(\text{ON})}$	Static Drain-to-Source On-Resistance	--	6.0	7.5	$\text{m}\Omega$	$V_{\text{GS}}=10\text{V}, I_D=60\text{A}$
$V_{\text{GS}(\text{TH})}$	Gate Threshold Voltage	2	--	4	V	$V_{\text{DS}}=V_{\text{GS}}, I_D=250\mu\text{A}$
Pulse width $\leqslant 300\mu\text{s}$ ; duty cycle $\leqslant 2\%$						

**Dynamic Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$C_{\text{iss}}$	Input Capacitance	--	4572	--	$\text{pF}$	$V_{\text{GS}}= 0\text{V}, V_{\text{DS}} = 25\text{V}$ $f = 1.0\text{MHz}$
$C_{\text{oss}}$	Output Capacitance	--	494.4	--		
$C_{\text{rss}}$	Reverse Transfer Capacitance	--	253	--		
$Q_g$	Total Gate Charge	--	74.4	--	$\text{nC}$	$I_D=60\text{A}, V_{\text{DD}}=64\text{V}$ $V_{\text{GS}} = 10\text{V}$
$Q_{\text{gs}}$	Gate-to-Source Charge	--	21.9	--		
$Q_{\text{gd}}$	Gate-to-Drain ("Miller") Charge	--	22.4	--		

**Resistive Switching Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$t_{\text{d}(\text{ON})}$	Turn-on Delay Time	--	35.7	--	$\text{ns}$	$V_{\text{DD}}=40\text{V}, I_D=60\text{A},$ $V_{\text{GS}}=10\text{V} R_G=6\Omega$
$t_{\text{rise}}$	Rise Time	--	65.6	--		
$t_{\text{d}(\text{OFF})}$	Turn-Off Delay Time	--	67.2	--		
$t_{\text{fall}}$	Fall Time	--	21.87	--		

**Source-Drain Diode Characteristics**T<sub>c</sub>=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I <sub>s</sub>	Continuous Source Current (Body Diode)	--	--	120	A	T <sub>c</sub> =25°C
I <sub>SM</sub>	Maximum Pulsed Current (Body Diode)	--	--	480	A	
V <sub>SD</sub>	Diode Forward Voltage	--	--	1.2	V	I <sub>SD</sub> =60A, V <sub>GS</sub> =0V I <sub>s</sub> = 20A di/dt=100A/us
t <sub>rr</sub>	Reverse Recovery Time	--	72	--	ns	
Q <sub>rr</sub>	Reverse Recovery Charge	--	126	--	nC	
Pulse width ≤300μs; duty cycle ≤ 2%						

## Notes:

\*1. Repetitive rating; pulse width limited by maximum junction temperature.

\*2. L=0.5mH, I<sub>D</sub>=51A, Start T<sub>J</sub>=25°C

### Characteristics Curve:

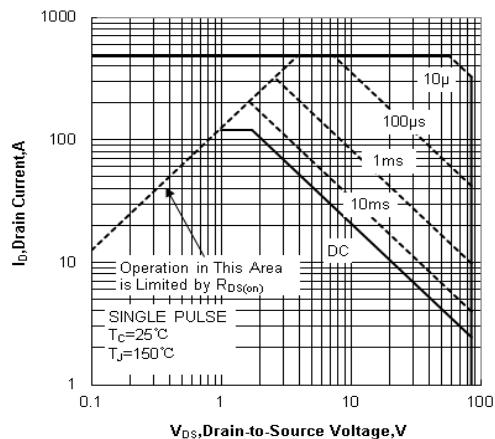


Figure 1 Maximum Forward Bias Safe Operating Area

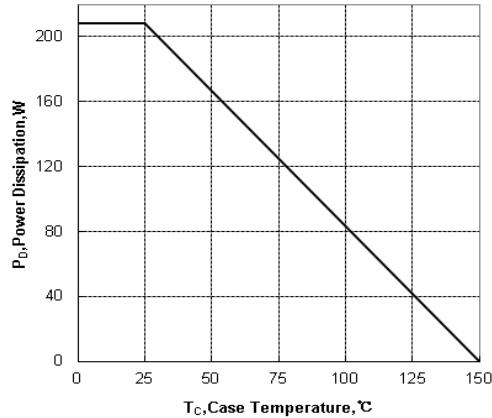


Figure 2 Maximum Power Dissipation vs Case Temperature

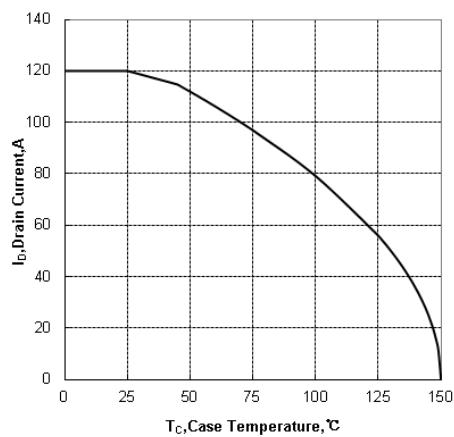


Figure 3 Maximum Continuous Drain Current vs Case Temperature

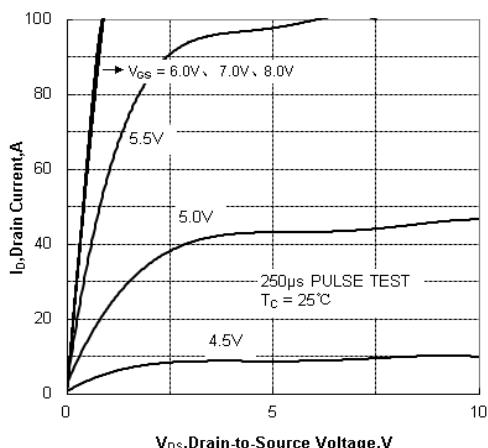


Figure 4 Typical Output Characteristics

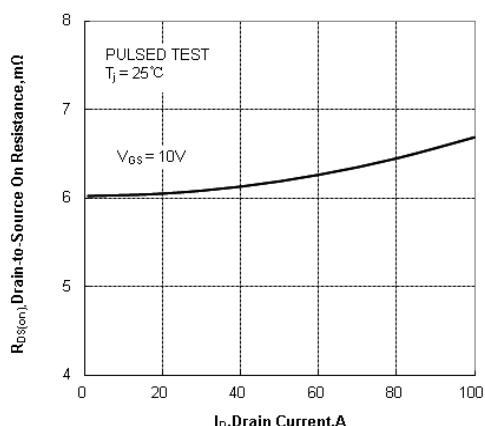


Figure 5 Drain-to-Source On Resistance vs Drain Current

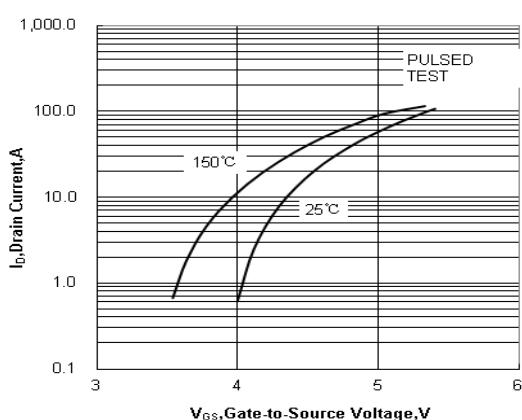


Figure 6 Typical Transfer Characteristics

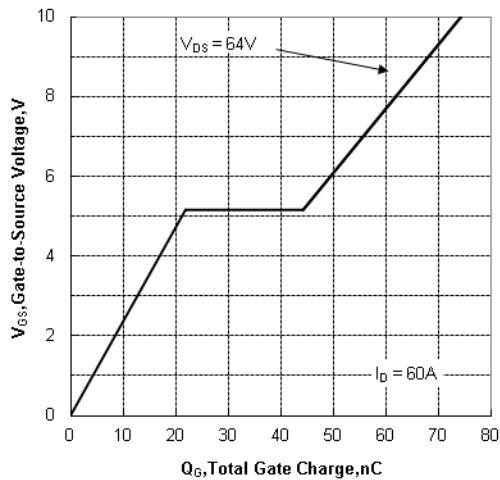


Figure 7 Typical Gate Charge vs Gate to Source Voltage

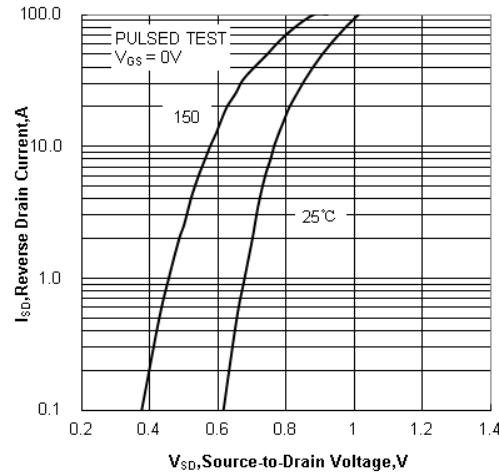


Figure 8 Typical Body Diode Transfer Characteristics

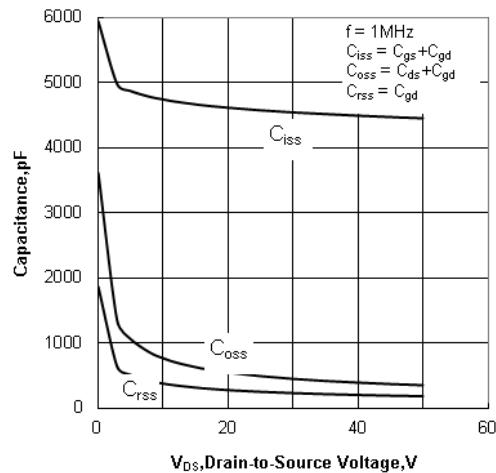


Figure 9 Typical Capacitance vs Drain to Source Voltage

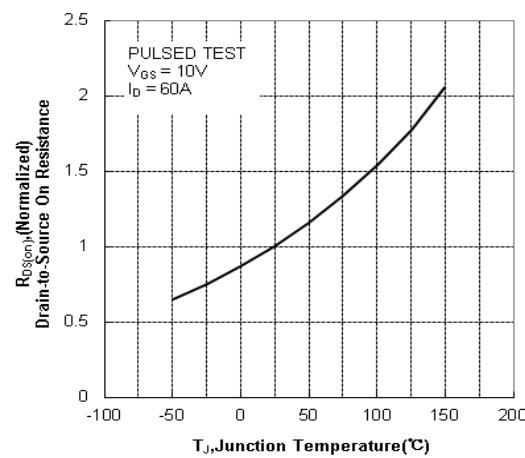


Figure10 Typical Drian to Source on Resistance vs Junction Temperature

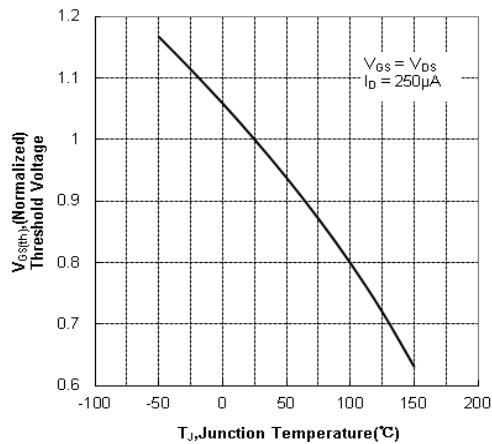


Figure11 Typical Threshold Voltage vs Junction Temperature

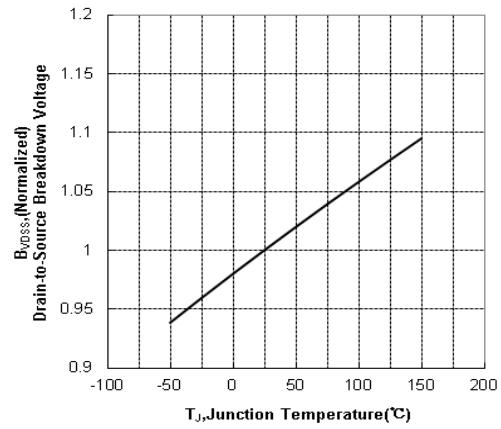


Figure12 Typical Breakdown Voltage vs Junction Temperature

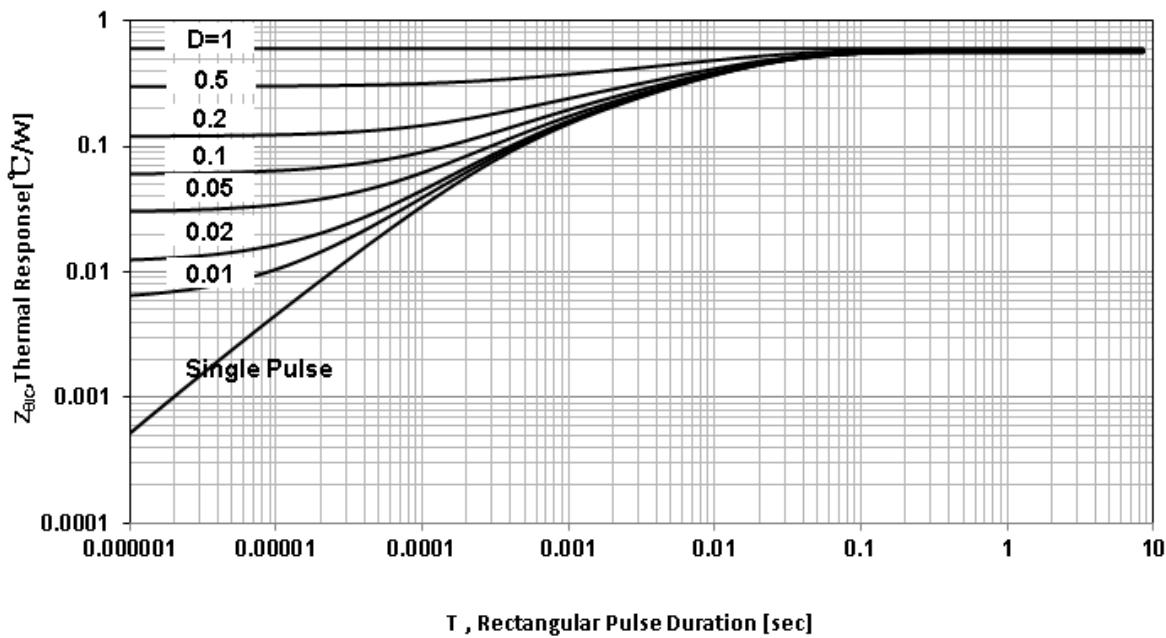


Figure 13 Maximum Effective Transient Thermal Impedance, Junction-to-Case

## Test Circuits and Waveforms

Figure 14. Gate Charge Test Circuit

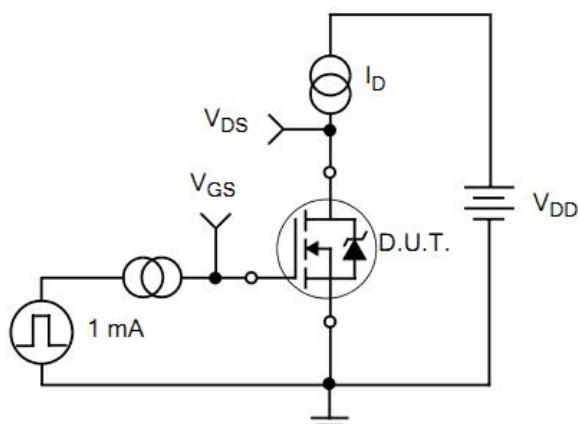


Figure 15. Gate Charge Waveforms

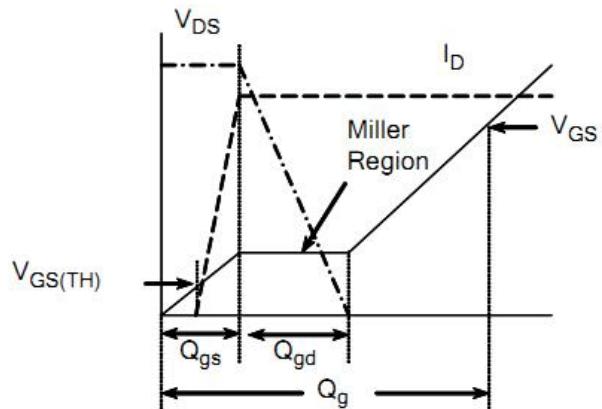


Figure 16. Resistive Switching Test Circuit

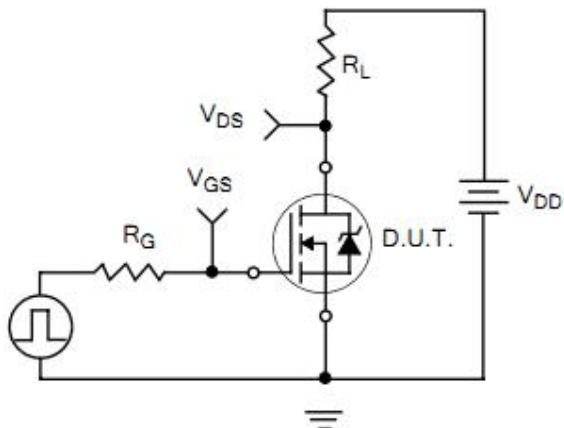
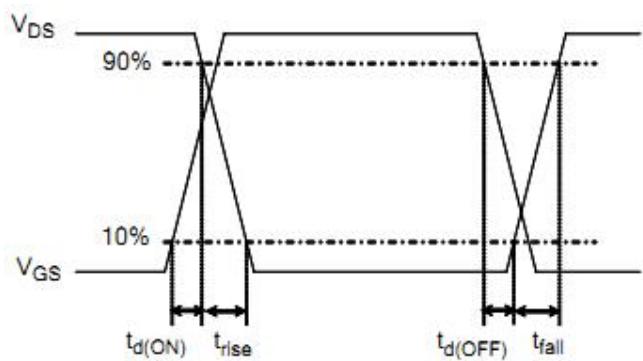
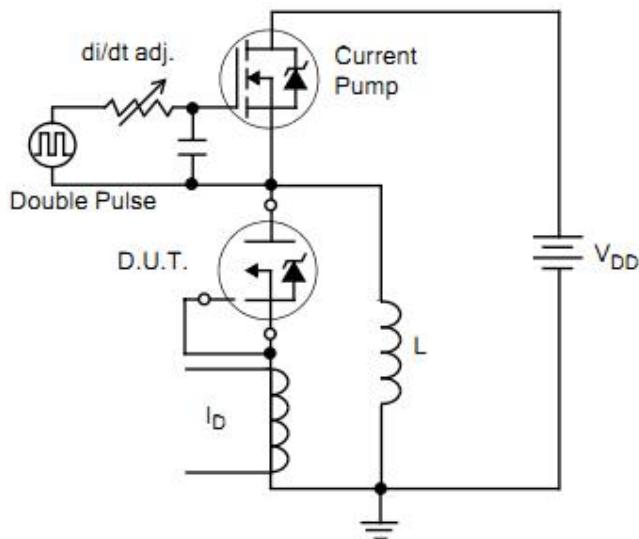


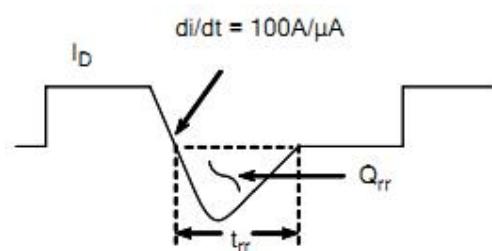
Figure 17. Resistive Switching Waveforms



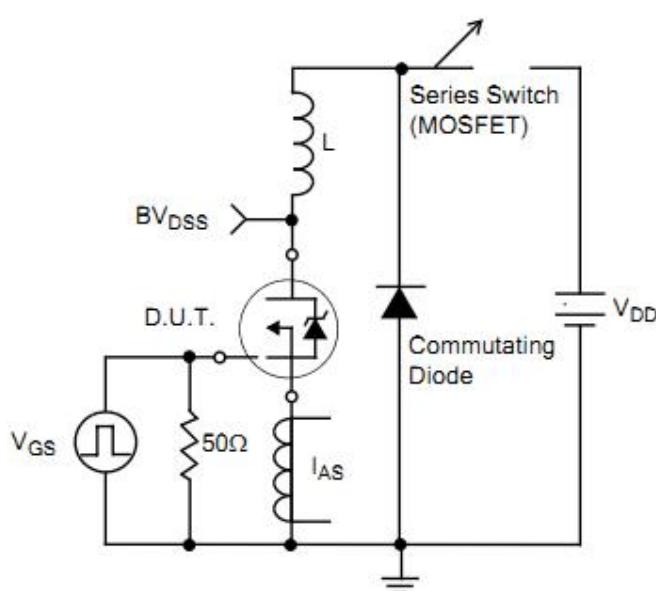
**Figure 18. Diode Reverse Recovery Test Circuit**



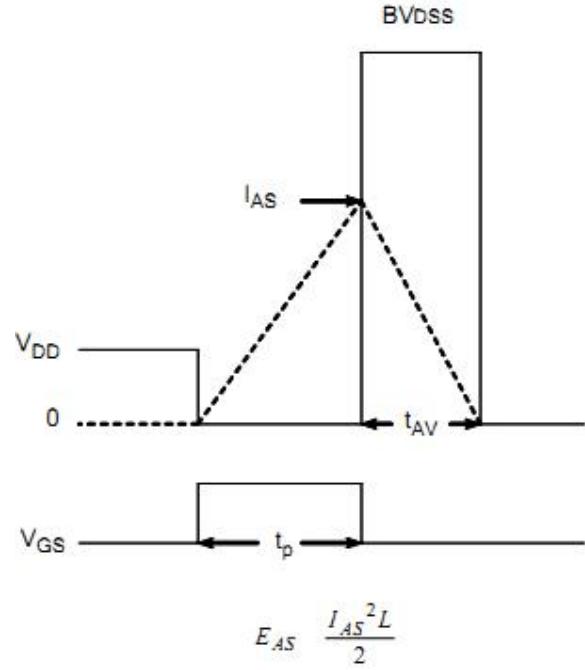
**Figure 19. Diode Reverse Recovery Waveform**



**Figure20.Unclamped Inductive Switching Test Circuit**



**Figure21.Unclamped Inductive Switching Waveform**



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